

LLNL Laser-Compton X-ray Characterization

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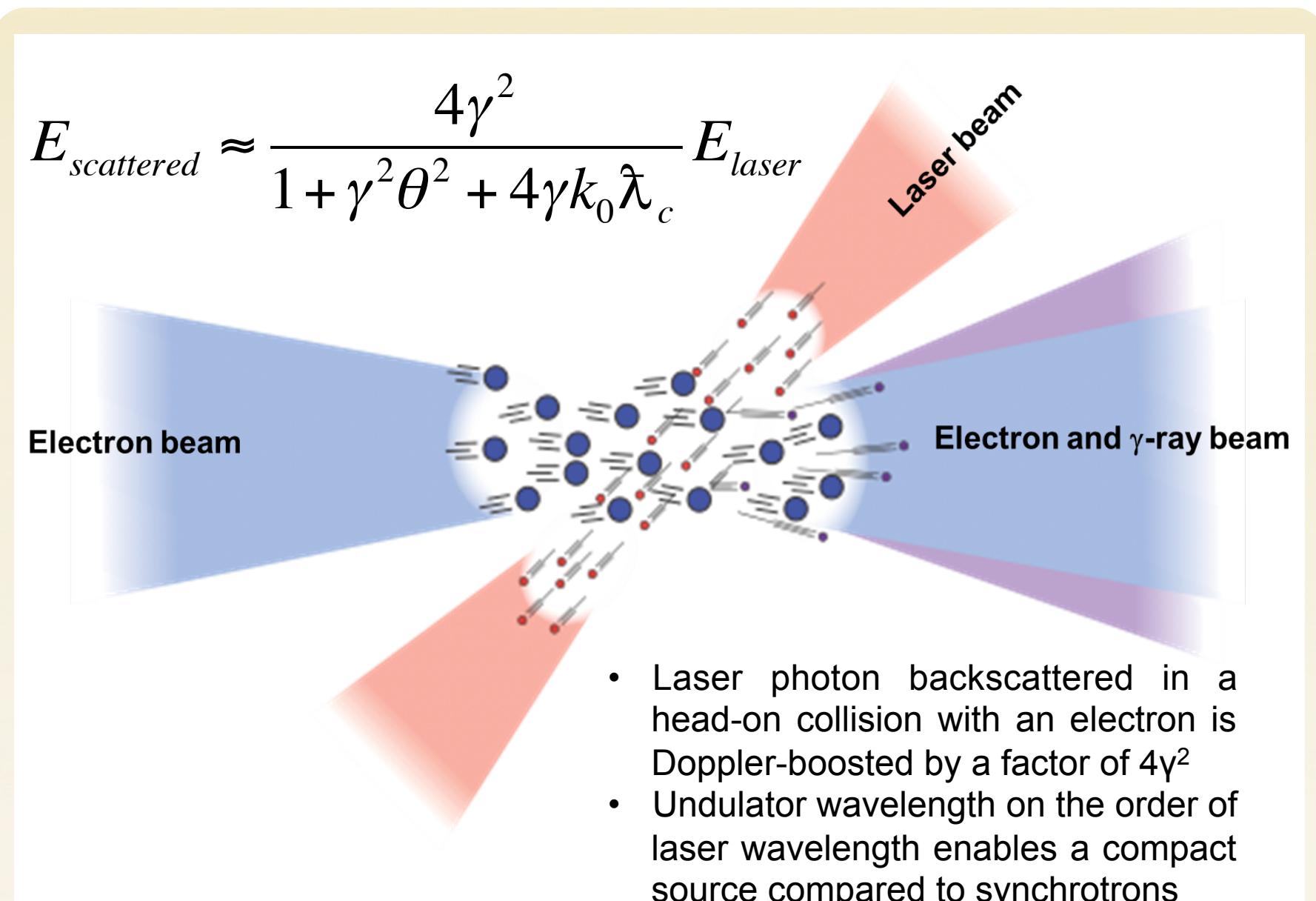
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Abstract

Laser-Compton X rays have been produced at LLNL, and results agree very well with modeling predictions. An X-ray CCD camera was calibrated for flux and resolution for characterization of the 30 keV X-ray beam. A resolution test pattern was imaged to measure the source size. K-edge absorption images using thin foils confirm narrow bandwidth and offer electron beam diagnostics.

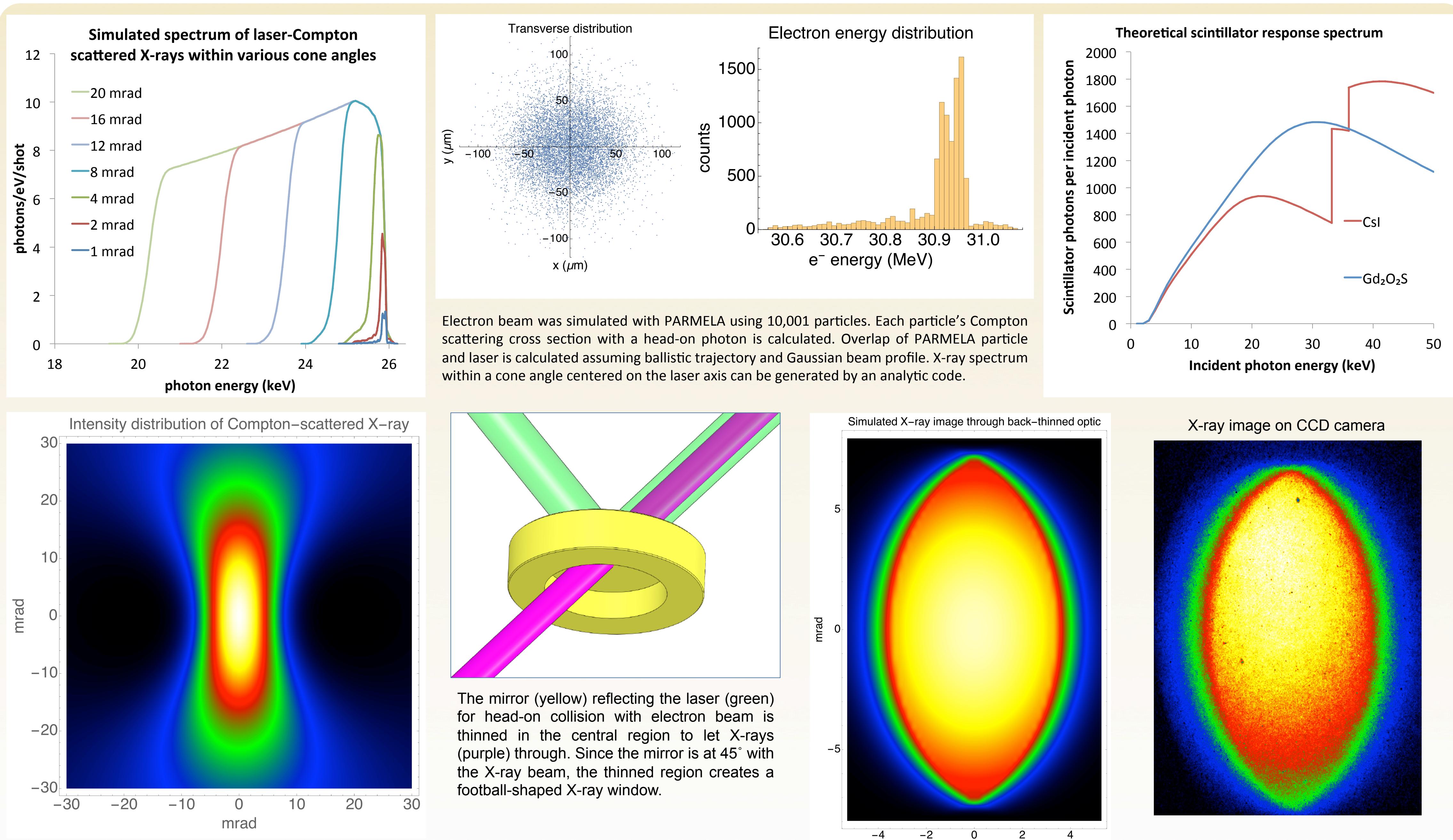


Laser-Compton X-rays

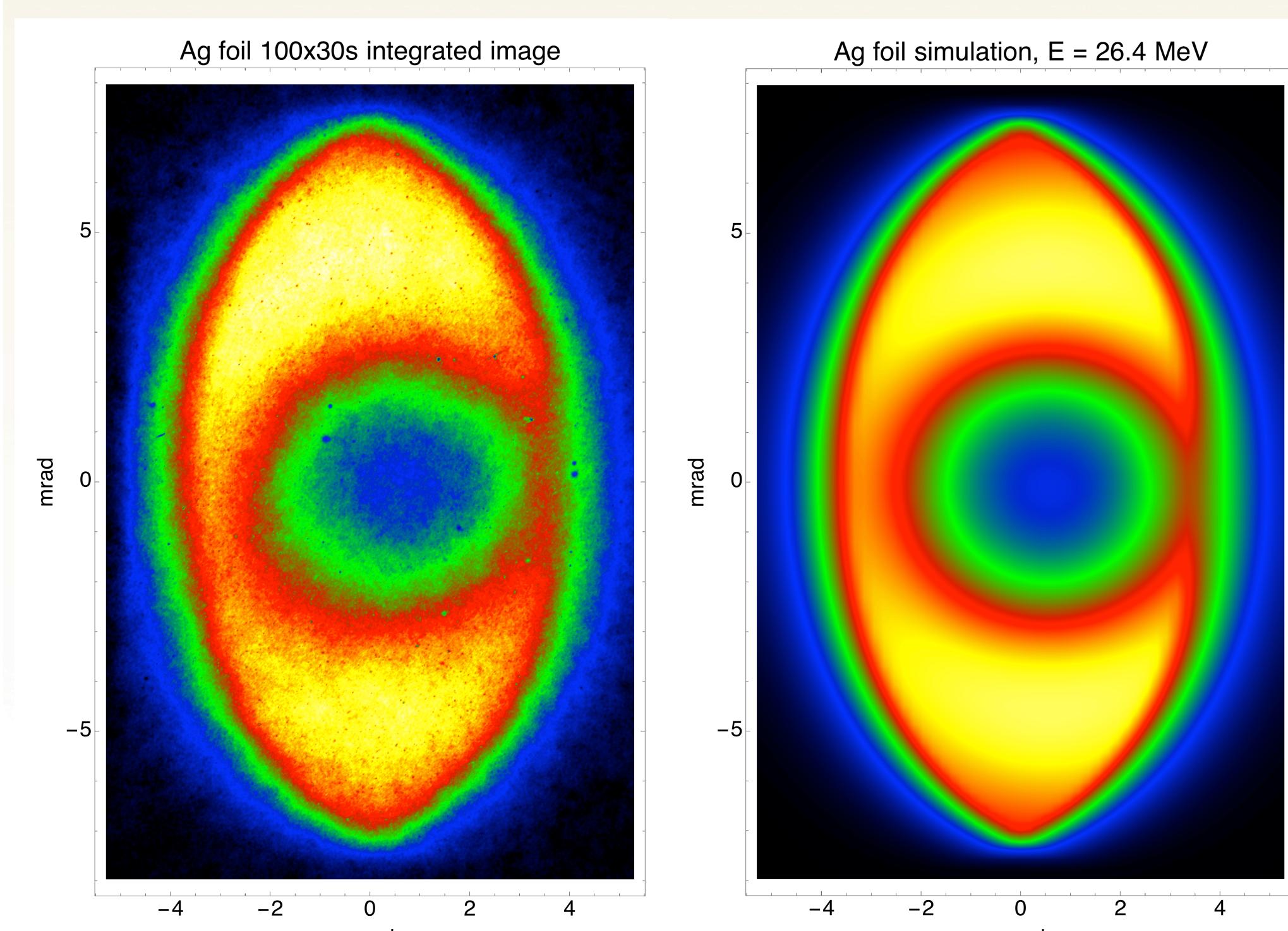
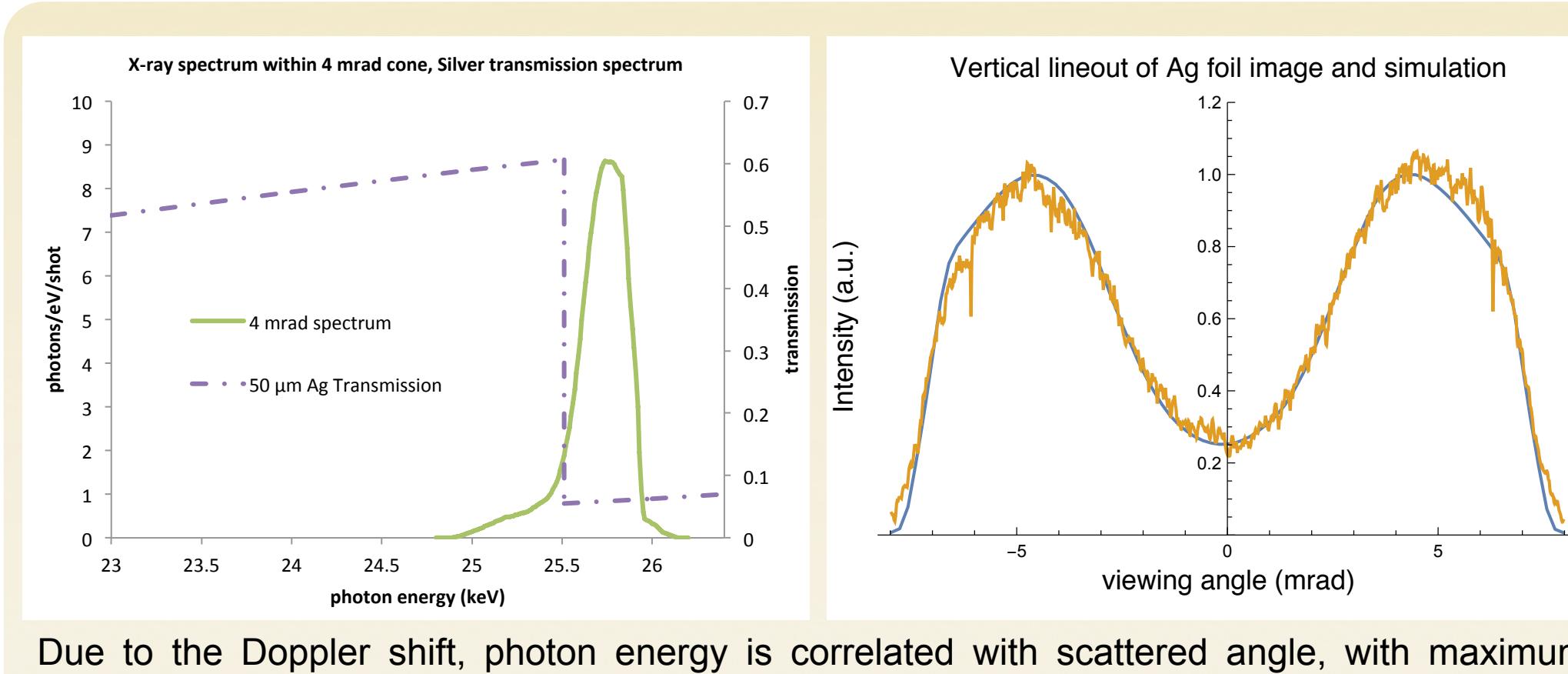


	Current Parameter	Upgrade Parameter	Upgrade Method	Capability
Pulse length	6ns	2ps	Install diode-pumped multi-Joule laser as ILS	>350x flux increase
Laser energy	750mJ	1J		
Repetition rate	10Hz	120Hz		
Bunches per pulse	1 to 4	1000		
Charge per bunch	100pC	25pC	Install GHz PDL and ILS recirculation	>60x flux increase
e ⁻ emittance	0.3μm	0.3μm		
e ⁻ energy	30MeV	90MeV	Install second section, RF pulse compressor	Dense material radiography
y energy	34keV	290keV		
		250MeV	Procure additional RF power and sections	Nuclear Resonance Fluorescence
2MeV				

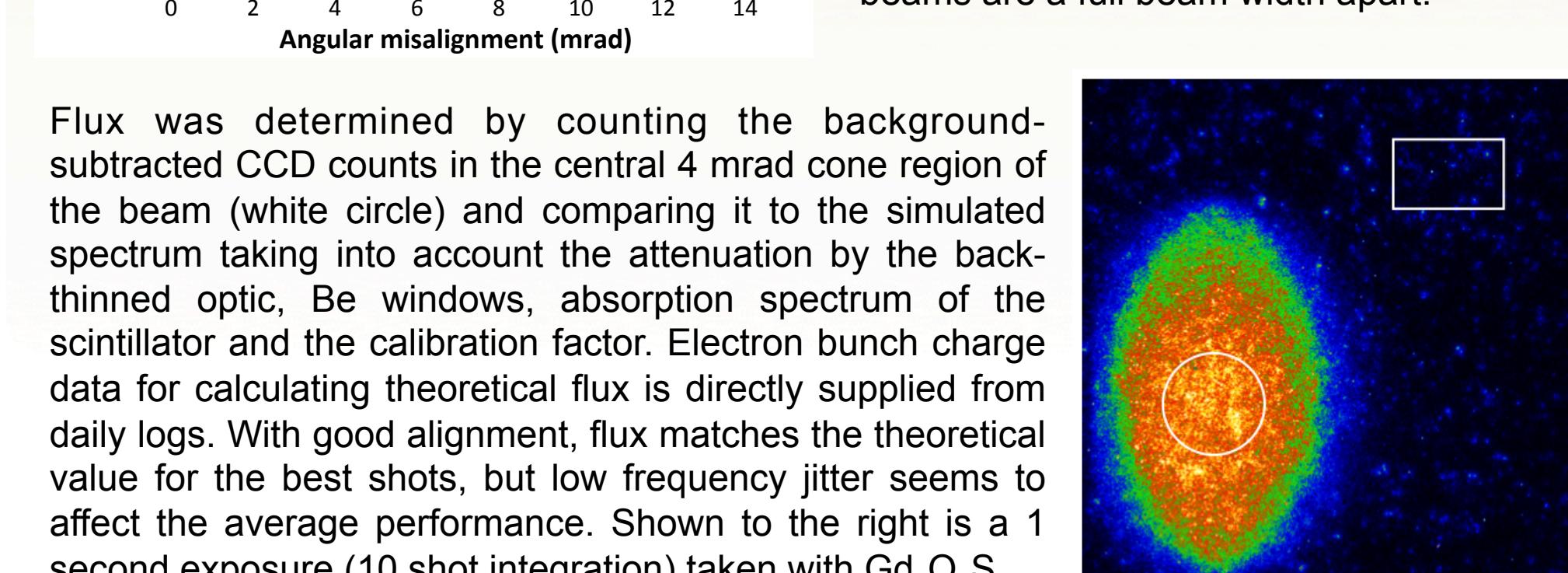
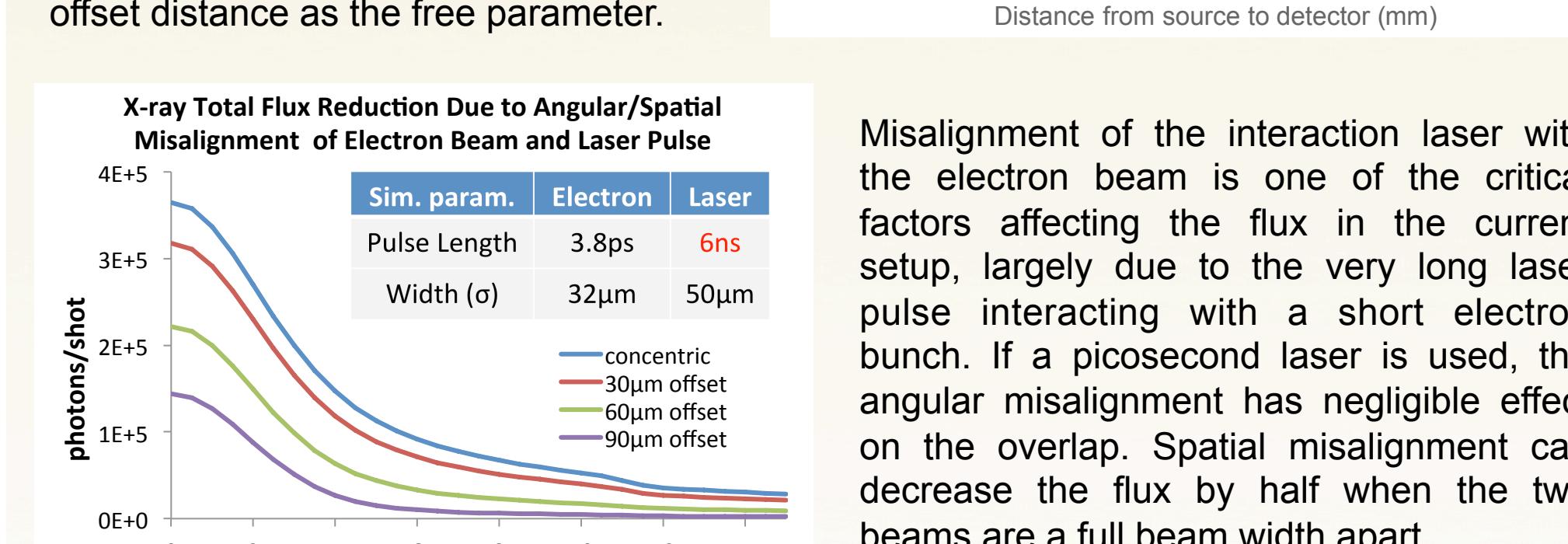
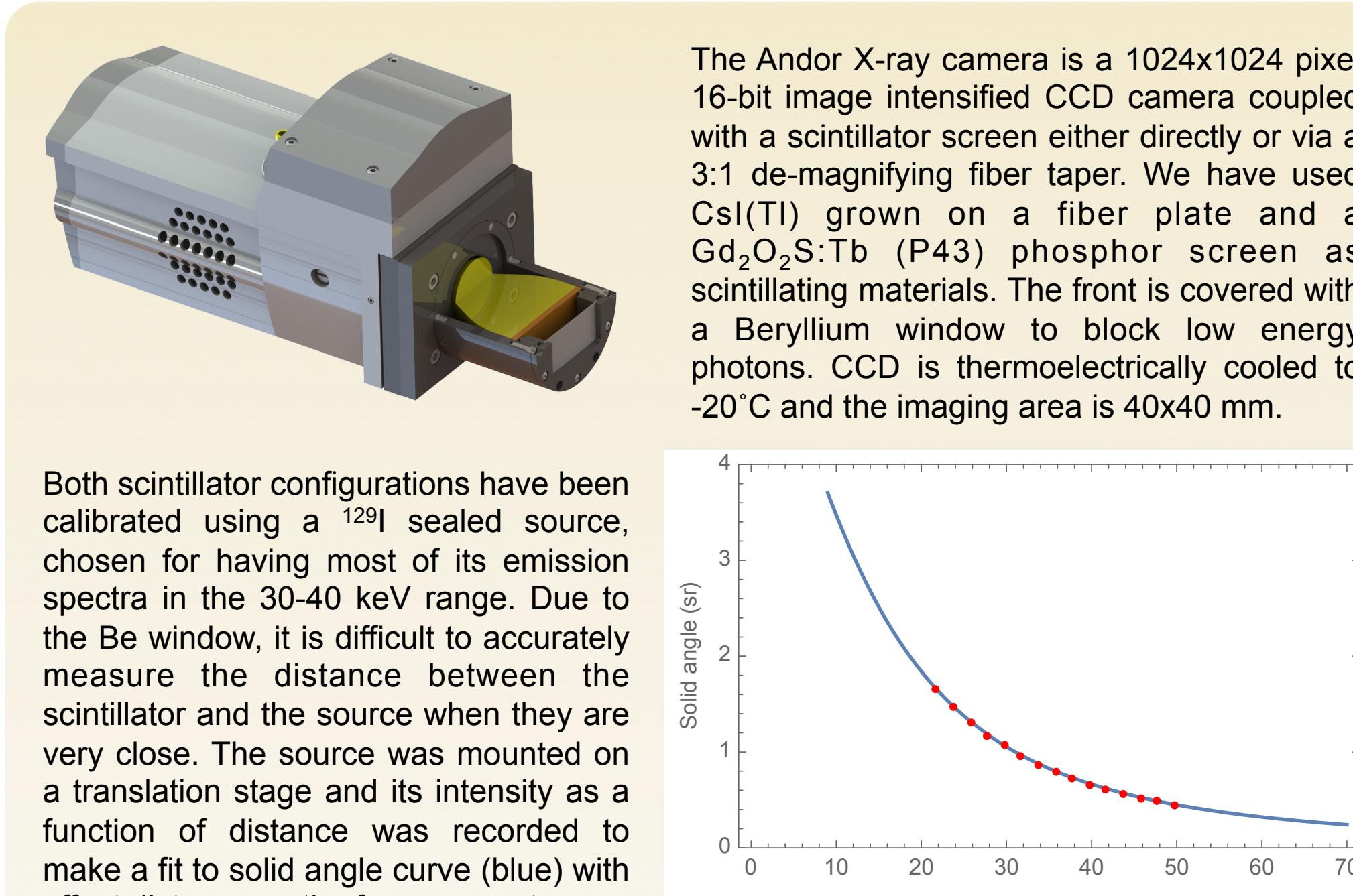
Spectral & spatial modeling of electron beam, X-rays and detection system



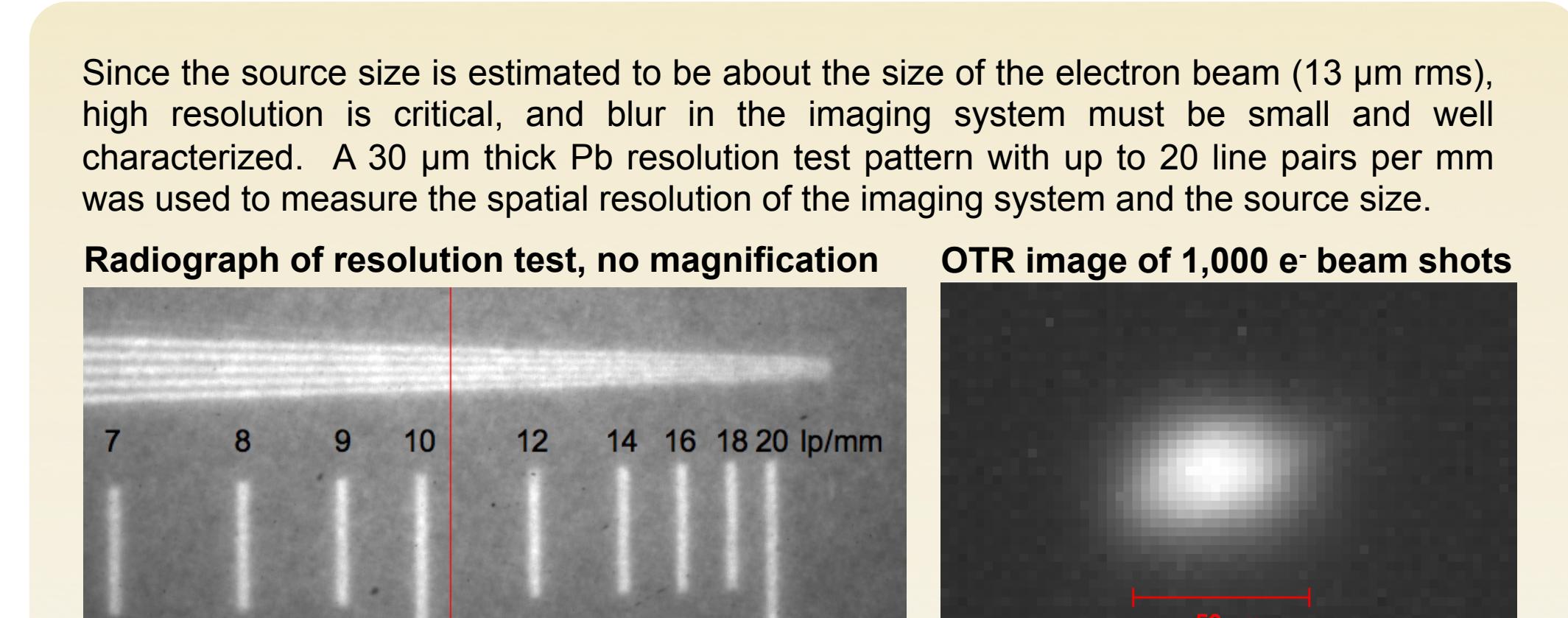
Narrow-bandwidth K-edge absorption



Camera calibration & flux measurement

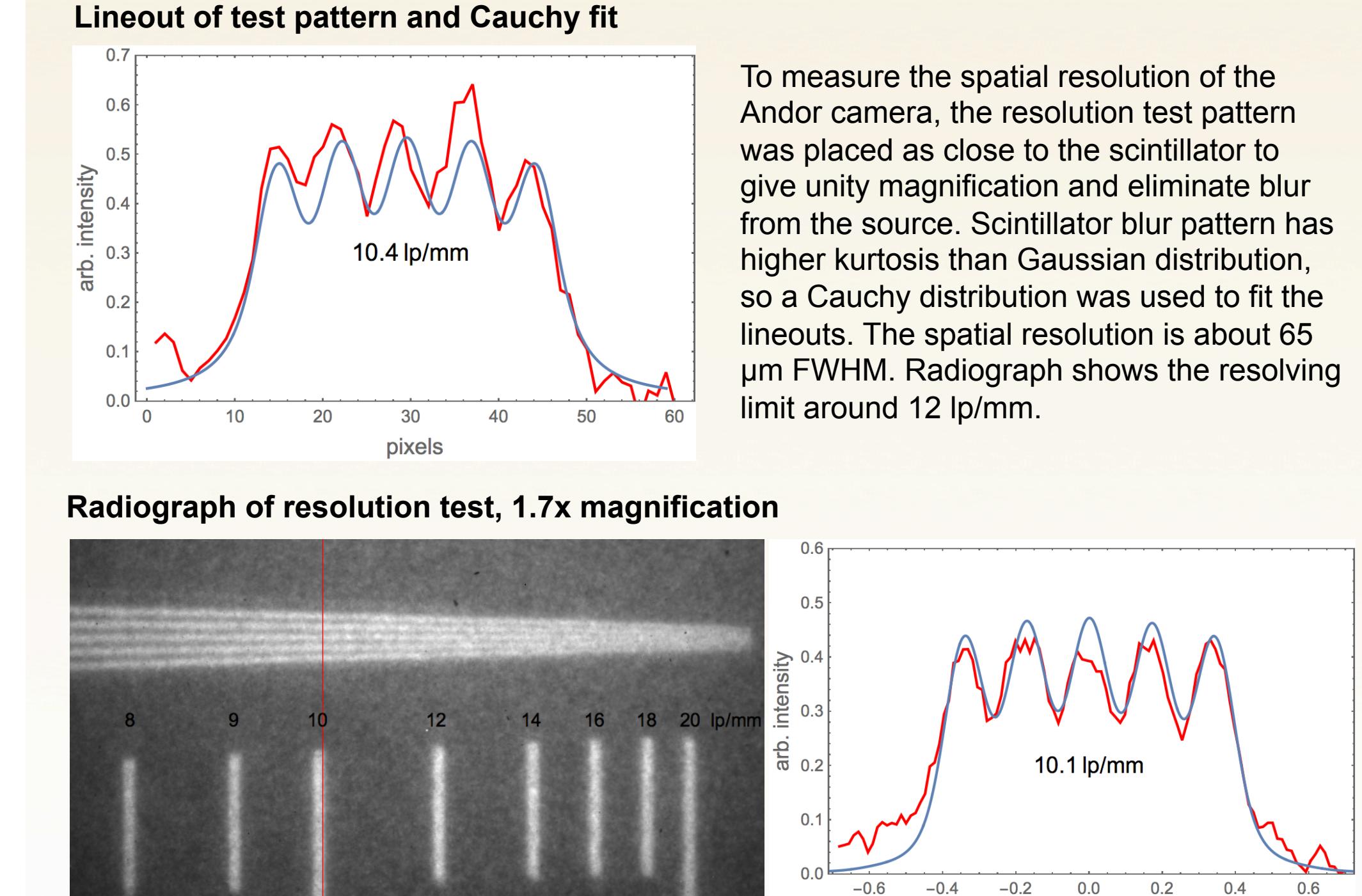


Resolution & source size measurement



Radiograph of resolution test, no magnification OTR image of 1,000 e⁻ beam shots

Lineout of test pattern and Cauchy fit



For the source size measurement, the test pattern was placed as close as possible to the interaction point so that the pattern image was magnified 1.7x. Blur pattern due to finite source size was found to be very close to Gaussian, so the fit to the magnified image was a Gaussian distribution further blurred by convolution with 65 μm FWHM Cauchy distribution, representing the imaging system blur. Source size is confirmed to be smaller than 100 μm FWHM, and measurement is limited by the imaging system resolution and signal-to-noise ratio.